



<b>Search Notes</b>  	Application/Control No.  09842596	Applicant(s)/Patent Under Reexamination  SHANTHAVEERAI AH ET AL.
	Examiner Nano, Sargon N	Art Unit 2157


Notes	Date	Examiner
EAST, Consulted with Primary Robert Harrell, Consulted with Primary Paul Myers	8/23/06 and 8/25/06	SN

U.S. Patent and Trademark Office	Part of Paper No.: 20060829
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<b>Interference Searched</b>  	Application/Control No.  09842596	Applicant(s)/Patent Under Reexamination  SHANTHAVEERAI AH ET AL.
	Examiner Nano, Sargon N	Art Unit 2157

Class	SubClass	Date	Examiner
709	220, 222, 207	08/29/2006	

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	<p>Examiner</p> <p>Nano, Sargon N</p>	<p>Art Unit</p> <p>2157</p>

Class	SubClass	Date	Examiner
709	220-224,227	08/29/2006	SN

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